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|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/714,642 | Applicant(s)/Patent Under Reexamination TAKENAKA ET AL. | |
| | Examiner Tan Le | Art Unit 3632 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-6,533,696 | 03-2003 | Takenaka et al. | 475/150 |
| * | B | US-6,166,498 | 12-2000 | Yamaguchi et al. | 318/34 |
| * | C | US-2005/0200061 | 09-2005 | Nemoto, Hirotomi | 267/140.14 |
| * | D | US-2004/0124332 | 07-2004 | Takenaka et al. | 248/648 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------------------|----------------|
| | N | JP-2000032607 | 01-2000 | Japan | Yamada | n/a |
| | O | EP 1000790 | 05-2000 | EPO | Yamaguchi et al. | n/a |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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